

**Double phase fault collapsing with linear complexity in digital circuits**

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**Fault collapsing in digital circuits using fast fault dominance and equivalence analysis with SSBDDs**

**Ubar, Raimund-Johannes; Jürimägi, Lembit; Orasson, Elmet; Raik, Jaan** VLSI-SoC : Design for Reliability, Security, and Low Power : 23rd IFIP WG 10.5/IEEE International Conference on Very Large Scale Integration, VLSI-SoC 2015 Daejeon, Korea, October 5-7, 2015 : revised selected papers 2016 / p. 23-45 : ill [http://dx.doi.org/10.1007/978-3-319-46097-0\\_2](http://dx.doi.org/10.1007/978-3-319-46097-0_2)

**Logic simulation and fault collapsing with shared structurally synthesized BDDs**

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